HD74LS170 ●4-by-4 Register File (with open collector outputs)

The HD74LS170 is organized as 4 words of 4 bits each and separate on-chip decoding is provided for addressing the four word locations to either write-in or retrieve data. This permits simultaneous writing into one location and reading from another word location.

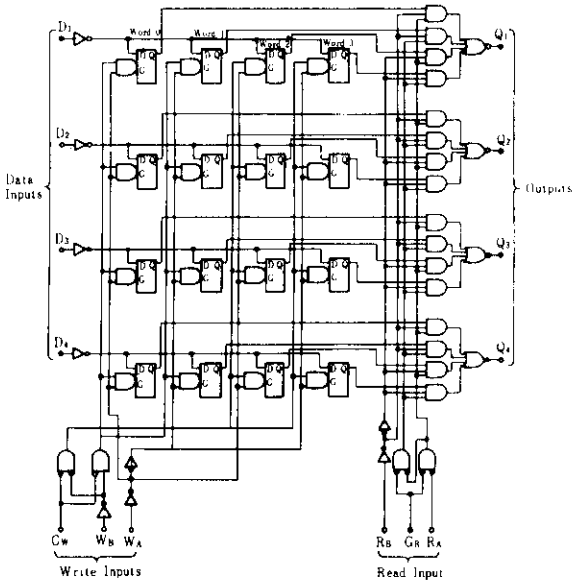
Four data inputs are available which are used to supply the 4-bit word to be stored. Location of the word is determined by the write-address inputs A and B in conjunction with a write-enable signal.

Data applied at the inputs should be in its true form. That is, if a high-level signal is desired from the output, a high level is applied at the data input for that particular bit location. The latch inputs are arranged so that new data will be accepted only if both internal address gate inputs are high. When this condition exists, data at the D input is transferred to the latch output. When the write-enable input, G_W, is high, the data inputs are inhibited and their levels can cause no change in the information stored in the internal latches.

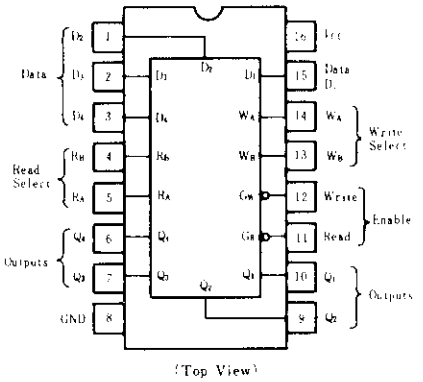
When the read-enable input, G_R, is high, the data outputs are inhibited and remain high, the individual address lines permit direct acquisition of data stored in any four of the latches. Four individual decoding gates are used to complete the address for reading a word.

When the read address is made in conjunction with the read-enable signal the word appears at the four outputs.

■BLOCK DIAGRAM



■PIN ARRANGEMENT



■FUNCTION TABLE

Write Inputs			Word			
W_B	W_A	G_W	0	1	2	3
L	L	L	Q=D	Q_0	Q_0	Q_0
L	H	L	Q_0	Q=D	Q_0	Q_0
H	L	L	Q_0	Q_0	Q=D	Q_0
H	H	L	Q_0	Q_0	Q_0	Q=D
×	×	H	Q_0	Q_0	Q_0	Q_0

Read Inputs			Outputs			
W_B	W_A	G_W	0	1	2	3
L	L	L	W_0B_1	W_0B_2	W_0B_3	W_0B_4
L	H	L	W_1B_1	W_1B_2	W_1B_3	W_1B_4
H	L	L	W_2B_1	W_2B_2	W_2B_3	W_2B_4
H	H	L	W_3B_1	W_3B_2	W_3B_3	W_3B_4
×	×	H	H	H	H	H

Notes: H = high level, L = low level, X = irrelevant.
(Q=D) = The four selected internal flip-flop outputs will assume the states applied to the four external data inputs.
Q_0 = The level of Q before the indicated input conditions were established.
W_0B_1 = The first bit of word 0, etc.

■RECOMMENDED OPERATING CONDITIONS

Item		Symbol	min	typ	max	Unit
Supply Voltage		V_{CC}	4.75	5	5.25	V
Output Voltage		V_{OH}	—	—	5.5	V
Output Current		I_{OL}	—	—	8	mA
Pulse width	Read enable	t_w	25	—	—	ns
	Write enable		60	—	—	
Setup Time	Data input	t_{su}	10	—	—	ns
	Write select		15	—	—	
Hold Time	Data input	t_h	15	—	—	ns
	Write select		5	—	—	
Latch time		t_{latch}	60	—	—	ns

■ELECTRICAL CHARACTERISTICS (Ta=−20～+75°C)

Item		Symbol	Test Condition		min	typ*	max	Unit
Input Voltage		V_{IH}			2.0	—	—	V
		V_{IL}			—	—	0.8	V
Output Current		I_{OH}	V_{CC}=4.75V, V_{OH}=5.5V, V_{IL}=0.8V, V_{IH}=2V		—	—	100	μA
Output Voltage		V_{OL}	V_{CC}=4.75V, V_{IH}=2V, V_{IL}=0.8V	I_{OL}=4mA	—	—	0.4	V
				I_{OL}=8mA	—	—	0.5	
Input Current	Any D, R or W	I_{IH}	V_{CC}=5.25V, V_I=2.7V		—	—	20	μA
	G_R or G_W				—	—	40	
	Any D, R or W	I_{IL}	V_{CC}=5.25V, V_I=0.4V		—	—	−0.4	mA
	G_R or G_W				—	—	−0.8	
	Any D, R or W	I_I	V_{CC}=5.25V, V_I=7V		—	—	0.1	mA
	G_R or G_W				—	—	0.2	
Supply Current		I_{CC}**	V_{CC}=5.25V		—	25	40	mA
Input clamp voltage		V_{IK}	V_{CC}=4.75V, I_{IN}=−18mA		—	—	−1.5	V

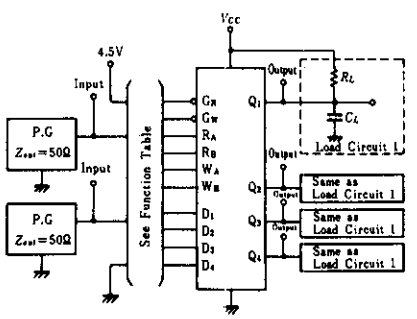
* V_{CC}=5V, Ta=25°C

** : Typical I_{CC} shown is an average for 50% duty cycle. Maximum I_{CC} is guaranteed for the following worst case conditions: 4.5V is applied to all data inputs and both enable inputs, all address inputs are grounded, and all outputs are open.

■SWITCHING CHARACTERISTICS (V_{CC}=5V, Ta=25°C)

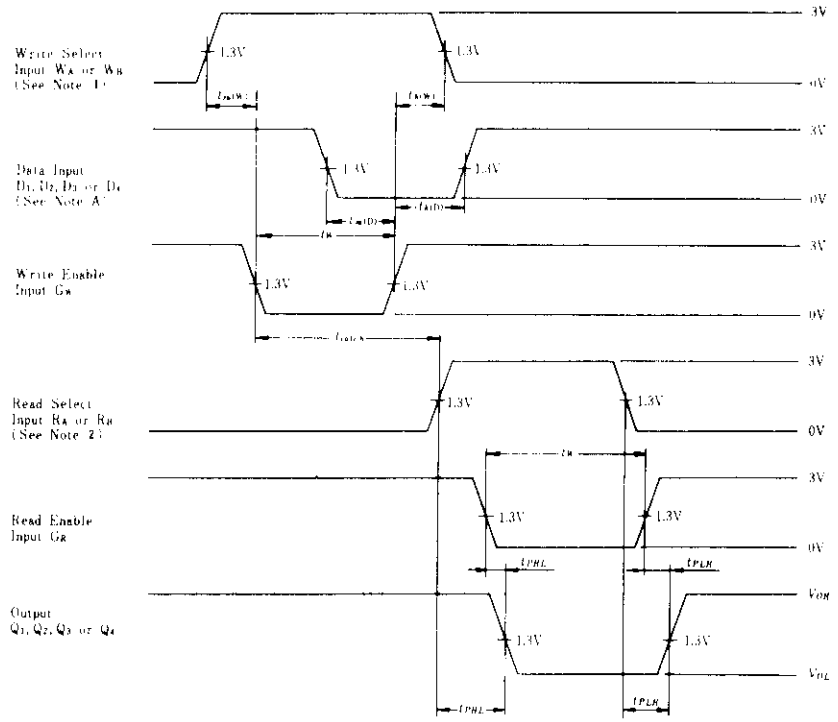
Item	Symbol	Inputs	Outputs	Test Conditions	min	typ	max	Unit
Propagation Delay Time	t_{PLH}	Read enable	Q_1～Q_4	C_L=15pF, R_L=2kΩ	—	20	30	ns
	t_{PHL}				—	20	30	
	t_{PLH}	Read select	Q_1～Q_4		—	25	40	
	t_{PHL}				—	24	40	
	t_{PLH}	Write enable	Q_1～Q_4		—	30	45	
	t_{PHL}				—	26	40	
	t_{PLH}	Data	Q_1～Q_4		—	30	45	
	t_{PHL}				—	22	30	

■TESTING METHOD



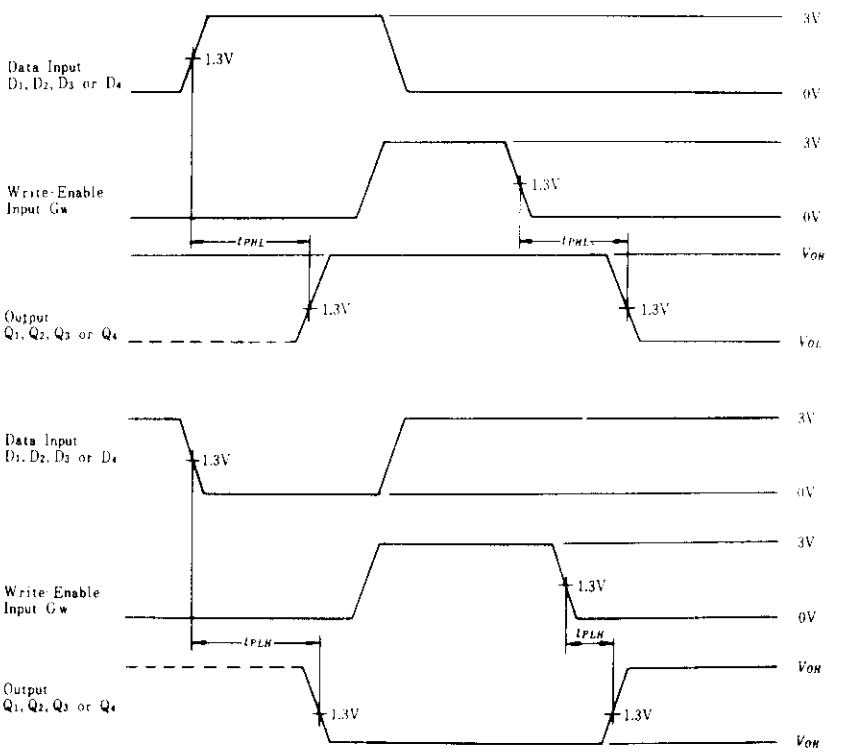
Notes: 1. C_L includes probe and jig capacitance.
2. All diodes are 1S2074 Ⓗ.

Waveform-1



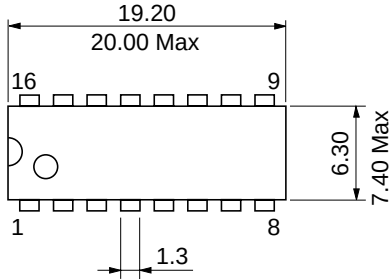
Notes:
1. High-level input pulses at the select and data inputs are illustrated in Waveform-1; however, times associated with low-level pulses are measured from the same reference points.
2. When measuring delay times from a read-select input, the read-enable input is low. When measuring delay times from the read-enable input, both read-select inputs have been established at steady states.
3. Input pulse; $t_{TLH} \leqq 15$ns, $t_{THL} \leqq 6$ns, $PRR \leqq 1$MHz, duty cycle 50%.

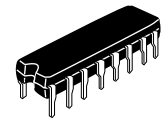
Waveform-2

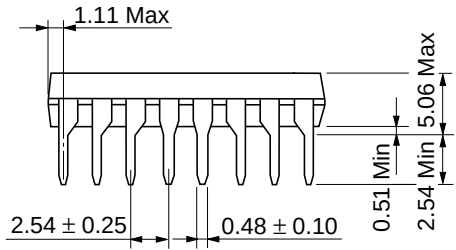


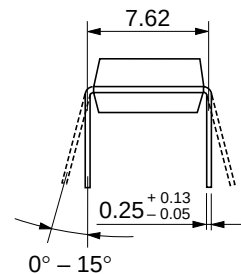
Note: In Waveform-2, each select address is tested. Prior to the start of each of the above tests, both write and read address inputs are stabilized with $W_A=R_A$ and $W_B=R_B$. During the test G_R is low.

Unit: mm



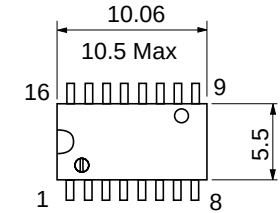


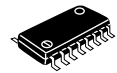


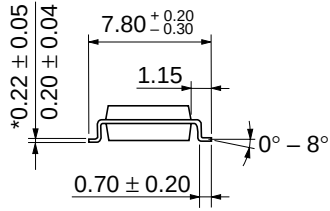


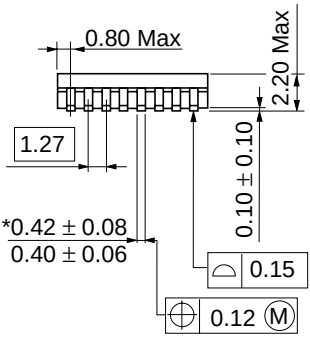
Hitachi Code	DP-16
JEDEC	Conforms
EIAJ	Conforms
Weight (reference value)	1.07 g

Unit: mm





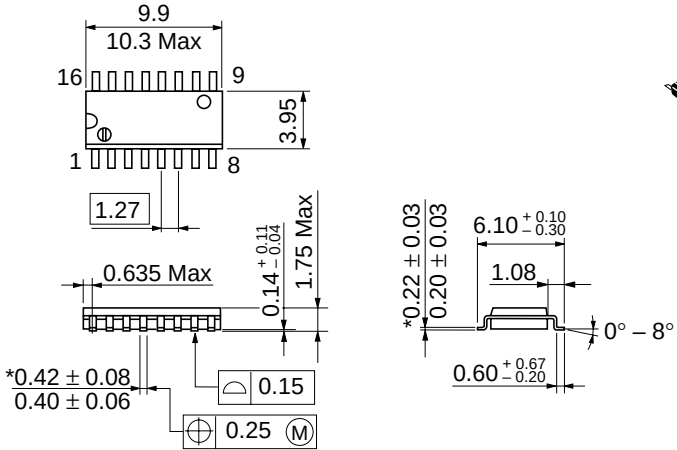


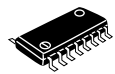


*Dimension including the plating thickness
Base material dimension

Hitachi Code	FP-16DA
JEDEC	—
EIAJ	Conforms
Weight (reference value)	0.24 g

Unit: mm





Hitachi Code	FP-16DN
JEDEC	Conforms
EIAJ	Conforms
Weight (reference value)	0.15 g

*Dimension including the plating thickness
Base material dimension

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